

**Notice of References Cited**

Application/Control No.

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Applicant(s)/Patent Under

Reexamination

BEATY ET AL.

Examiner

Sheela C Chawan..

Art Unit

2625

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**NON-PATENT DOCUMENTS**

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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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